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Nota di contenuto	An Engineer's Guide to Automated Testing of High-Speed Interfaces; Contents; Preface; Acknowledgments; 1 Introduction; 2 High-Speed Digital BasicsThis; 3 High-Speed Interface Standards; 4 ATE Instrumentation for DigitalApplications; 5 Tests and Measurements; 6 Production Testing; 7 Support Instrumentation; 8 Test Fixture Design; 9 Advanced ATE Topics; A Introduction to the Gaussian Distribution and Analytical Computation of the BER; B The Dual Dirac Model and RJ/DJ Separation; C Pseudo-Random Bit Sequences and Other Data Patterns; D Coding, Scrambling, Disparity,and CRC E Time Domain Reflectometry andTime Domain Transmission(TDR/TDT) F S-Parameters; G Engineering CAD Tools; H Test Fixture Evaluation andCharacterization; I Jitter Injection Calibration; About the Authors; Index
Sommario/riassunto	Providing a complete introduction to the state-of-the-art in high-speed digital testing with automated test equipment (ATE), this practical resource is the first book to focus exclusively on this increasingly important topic. Featuring clear examples, this one-stop reference covers all critical aspects of the subject, from high-speed digital basics, ATE instrumentation for digital applications, and test and measurements, to production testing, support instrumentation and text fixture design. This in-depth volume also discusses advanced ATE

topics, such as multiplexing of ATE pin channels and testing of high-speed bi-directional interfaces with fly-by approaches.